

### FQD4P25TM\_WS-VB Datasheet

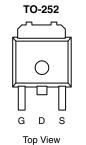
#### **Power MOSFET**

PRODUCT SUMMARY				
V <sub>DS</sub> (V)	- 250			
R <sub>DS(on)</sub> (Ω)	V <sub>GS</sub> = - 10 V	1.0		
Q <sub>g</sub> (Max.) (nC)	38			
Q <sub>gs</sub> (nC)	8.0			
Q <sub>gd</sub> (nC)	18			
Configuration	Single			

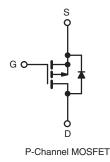
#### **FEATURES**

- Advanced Process Technology
- Dynamic dV/dt Rating
- 150 °C Operating Temperature
- · Fast Switching
- P-Channel
- · Fully Avalanche Rated
- Lead (Pb)-free Available





Drain Connected to Tab



<b>ABSOLUTE MAXIMUM RATINGS</b> T	<sub>C</sub> = 25 °C, u	nless otherw	ise noted			
PARAMETER			SYMBOL	MBOL LIMIT		
Drain-Source Voltage			V <sub>DS</sub>	- 250	v	
Gate-Source Voltage			V <sub>GS</sub>	± 20	v	
Continuous Drain Current	$V_{GS} \text{ at - 10 V} \frac{T_C = 25 \text{ °C}}{T_C = 100 \text{ °C}}$	T <sub>C</sub> = 25 °C	I <sub>D</sub> -	- 6.0	А	
		T <sub>C</sub> = 100 °C		- 4.0		
Pulsed Drain Current <sup>a</sup>			I <sub>DM</sub>	- 16		
Linear Derating Factor				0.28	W/°C	
Single Pulse Avalanche Energy <sup>b</sup>			E <sub>AS</sub>	520	mJ	
Repetitive Avalanche Current <sup>a</sup>			I <sub>AR</sub>	- 4.1	А	
Repetitive Avalanche Energy <sup>a</sup>			E <sub>AR</sub>	3.5	mJ	
aximum Power Dissipation $T_{\rm C} = 25 ^{\circ}{\rm C}$		PD	85	W		
Peak Diode Recovery dV/dt <sup>c</sup>			dV/dt	- 5.0	V/ns	
Operating Junction and Storage Temperature Range			T <sub>J</sub> , T <sub>stg</sub>	- 55 to + 150	°C	
Soldering Recommendations (Peak Temperature)	for	10 s		300 <sup>d</sup>		
Mounting Torquo	6 22 or 1	C 00 or M0 oprovi		10	lbf ⋅ in	
Mounting Torque	6-32 or M3 screw			1.1	N · m	

#### Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. Starting  $T_J = 25 \text{ °C}$ , L = 62 mH,  $R_G = 25 \Omega$ ,  $I_{AS} = -4.1 \text{ A}$  (see fig. 12). c.  $I_{SD} \le -4.1 \text{ A}$ , dl/dt  $\le -640 \text{ A/}\mu\text{s}$ ,  $V_{DD} \le V_{DS}$ ,  $T_J \le 150 \text{ °C}$ .

d. 1.6 mm from case.

\* Pb containing terminations are not RoHS compliant, exemptions may apply

### FQD4P25TM\_WS-VB



THERMAL RESISTANCE RATINGS					
PARAMETER	SYMBOL	TYP.	MAX.	UNIT	
Maximum Junction-to-Ambient	R <sub>thJA</sub>	-	65	°C/W	
Maximum Junction-to-Case (Drain)	R <sub>thJC</sub>	-	3.6	C/W	

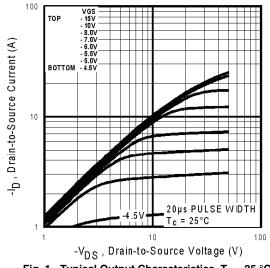
PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static							
Drain-Source Breakdown Voltage	V <sub>DS</sub>	$V_{GS} = 0 \text{ V}, \text{ I}_{D} = 250 \mu\text{A}$		- 250	-	-	V
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_J$	Reference	Reference to 25 °C, I <sub>D</sub> = 1 mA		- 0.27	-	V/°C
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> =	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 250 μA		-	- 4.0	V
Gate-Source Leakage	I <sub>GSS</sub>		V <sub>GS</sub> = ± 20 V	-	-	± 100	nA
Zarra Casta Malta na Dunin Currant	1	V <sub>DS</sub> =	- 250 V, V <sub>GS</sub> = 0 V	-	-	- 25	μΑ
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> = - 200	V, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 150 °C	-	-	- 250	
Drain-Source On-State Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = - 10 V	I <sub>D</sub> = - 2.5 A <sup>b</sup>	-	1.0	-	Ω
Forward Transconductance	<b>g</b> <sub>fs</sub>	V <sub>DS</sub> =	- 50 V, I <sub>D</sub> = - 4.1 A <sup>b</sup>	2.2	-	-	S
Dynamic							
Input Capacitance	C <sub>iss</sub>		V <sub>GS</sub> = 0 V,		680	-	
Output Capacitance	C <sub>oss</sub>		V <sub>DS</sub> = - 25 V,	-	170	-	1
Reverse Transfer Capacitance	C <sub>rss</sub>	f = 1	.0 MHz, see fig. 5	-	40	-	- pF
Drain to Sink Capacitance	С		f = 1.0 MHz	-	12	-	
Total Gate Charge	Qg			-	-	38	
Gate-Source Charge	Q <sub>gs</sub>	V <sub>GS</sub> = - 10 V	$V_{GS} = -10 V$ $I_D = -4.1 A, V_{DS} = -200 V,$ see fig. 6 and 13 <sup>b</sup>		-	8.0	nC
Gate-Drain Charge	Q <sub>gd</sub>		see lig. o and ro	-	-	18	1
Turn-On Delay Time	t <sub>d(on)</sub>		•	-	12	-	
Rise Time	t <sub>r</sub>		· 130 V, I <sub>D</sub> = - 4.1 A,	-	23	-	
Turn-Off Delay Time	t <sub>d(off)</sub>	R <sub>G</sub> = 12 Ω, R <sub>D</sub> = 31 Ω, see fig. 10 <sup>b</sup>		-	34	-	- ns
Fall Time	t <sub>f</sub>			-	21	-	
Internal Drain Inductance	L <sub>D</sub>	Between lead, 6 mm (0.25") from package and center of die contact		-	4.5	-	
Internal Source Inductance	L <sub>S</sub>			-	7.5	-	nH
Drain-Source Body Diode Characteristic	s					1	
Continuous Source-Drain Diode Current	۱ <sub>S</sub>	MOSFET symbol showing the integral reverse p - n junction diode		-	-	- 4.1	Α
Pulsed Diode Forward Current <sup>a</sup>	I <sub>SM</sub>			-	-	- 16	
Body Diode Voltage	$V_{SD}$	$T_{J} = 25 \ ^{\circ}C, I_{S} = -4.1 \ A, V_{GS} = 0 \ V^{b}$		-	-	- 6.5	V
Body Diode Reverse Recovery Time	t <sub>rr</sub>	- T <sub>J</sub> = 25 °C, I <sub>F</sub> = - 4.1 A, dl/dt = -100 A/µs <sup>b</sup> ·		-	190	290	ns
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>			-	1.5	2.2	μC
Forward Turn-On Time	t <sub>on</sub>	Intrinsic turn-on time is negligible (turn-on is dominated by $L_S$ and $L_D$ )					L <sub>D</sub> )

#### Notes

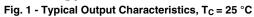
a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).

b. Pulse width  $\leq$  300  $\mu s;$  duty cycle  $\leq$  2 %.





#### TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



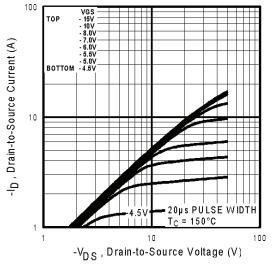
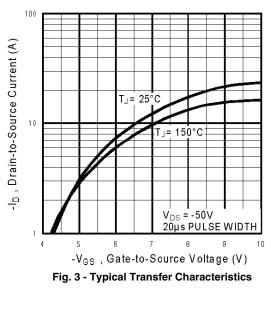


Fig. 2 - Typical Output Characteristics, T <sub>C</sub>= 150 °C



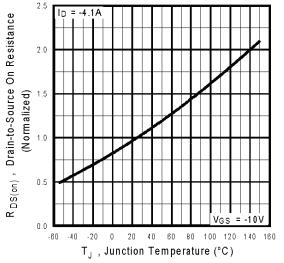


Fig. 4 - Normalized On-Resistance vs. Temperature

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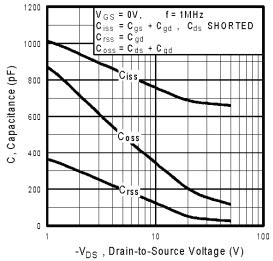


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

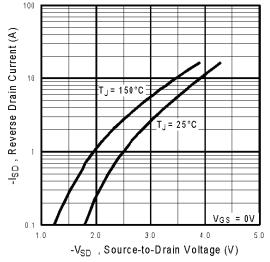


Fig. 7 - Typical Source-Drain Diode Forward Voltage

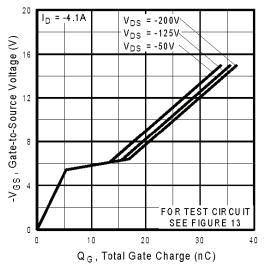


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

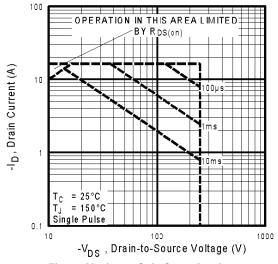


Fig. 8 - Maximum Safe Operating Area

### FQD4P25TM\_WS-VB



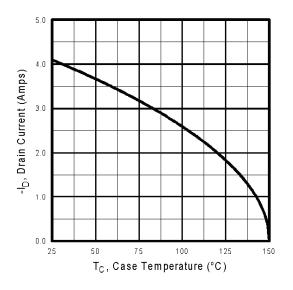


Fig. 9 - Maximum Drain Current vs. Case Temperature

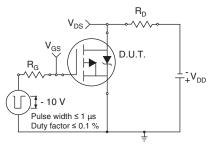


Fig. 10a - Switching Time Test Circuit

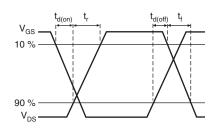


Fig. 10b - Switching Time Waveforms

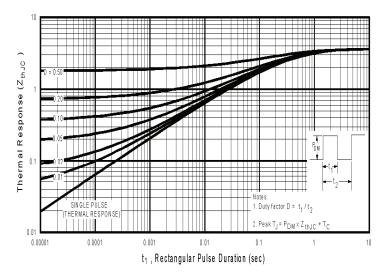


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

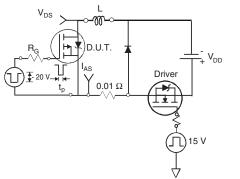


Fig. 12a - Unclamped Inductive Test Circuit

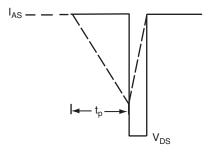


Fig. 12b - Unclamped Inductive Waveforms



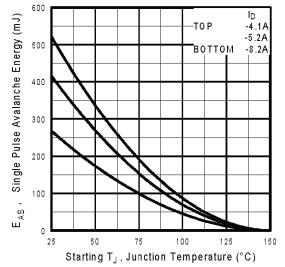


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

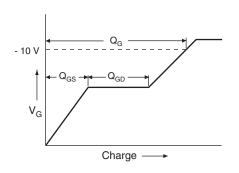
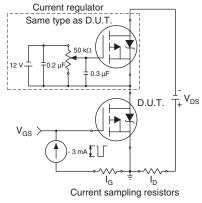
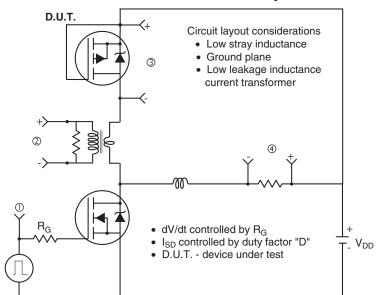


Fig. 13a - Basic Gate Charge Waveform









#### Peak Diode Recovery dV/dt Test Circuit

• Compliment N-Channel of D.U.T. for driver

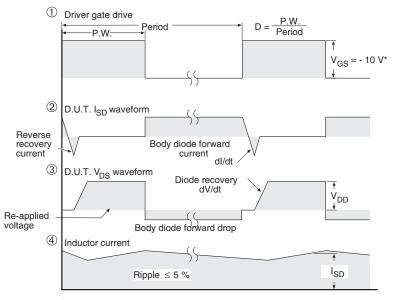
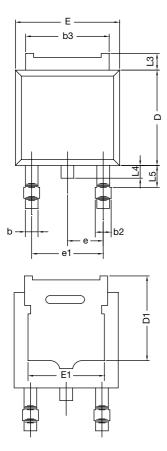


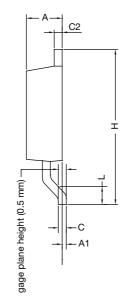


Fig. 14 - For P-Channel



## **TO-252AA CASE OUTLINE**





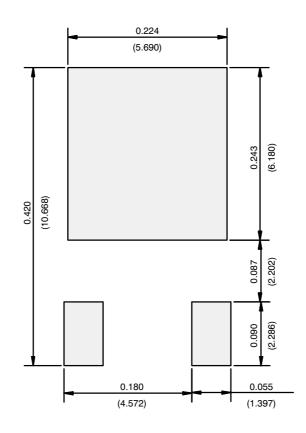
	MILLIN	IETERS	INCHES		
DIM.	MIN.	MAX.	MIN.	MAX.	
А	2.18	2.38	0.086	0.094	
A1	-	0.127	-	0.005	
b	0.64	0.88	0.025	0.035	
b2	0.76	1.14	0.030	0.045	
b3	4.95	5.46	0.195	0.215	
С	0.46	0.61	0.018	0.024	
C2	0.46	0.89	0.018	0.035	
D	5.97	6.22	0.235	0.245	
D1	5.21	-	0.205	-	
E	6.35	6.73	0.250	0.265	
E1	4.32	-	0.170	-	
Н	9.40	10.41	0.370	0.410	
е	2.28	BSC	0.090 BSC		
e1	4.56	BSC	0.180 BSC		
L	1.40	1.78	0.055	0.070	
L3	0.89	1.27	0.035	0.050	
L4	-	1.02	-	0.040	
L5	1.14	1.52	0.045	0.060	
ECN: X12-0247-Rev. M, 24-Dec-12 DWG: 5347					

Note

• Dimension L3 is for reference only.



#### **RECOMMENDED MINIMUM PADS FOR DPAK (TO-252)**



Recommended Minimum Pads Dimensions in Inches/(mm)



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